

**Search Notes**

Application/Control No.

10/807,636

Examiner

Nam Huynh

Applicant(s)/Patent under  
Reexamination

CHEN ET AL.

Art Unit

2617

**SEARCHED**

Class	Subclass	Date	Examiner
455	458	5/16/2006	NTH
	403		
	422.1		
	456.2		

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
See EAST search notes.	5/16/2006	NTH